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PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant:	Keiji Yada, et al.)	Examiner:	Kao, Chih Cheng G.
Serial No.:	10/719,887)	Art Unit:	2882
Filed:	November 21, 2003)	Our Ref:	B-5308 621524-7
For:	"X-RAY MICROSCOPIC INSPECTION APPARATUS")	Date:	May 20, 2005
)	Re:	<i>Amendment and Response</i>

AMENDMENT AND RESPONSE

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

This is in reply to the non-final Office Action mailed on February 23, 2005, an initial response to which is due no later than

May 23, 2005.

Please amend the above-identified application as described below and consider the following remarks. **All amendments and remarks herein are made without prejudice.**

Amendments to the Claims are reflected in the listing of claims that begins on page 2 of this paper.

Amendments to the Drawings begin on page 5 of this paper and include an attached replacement sheet.

Remarks/Arguments begin on page 6 of this paper.